

# EUROPEAN PATENT OFFICE

## Patent Abstracts of Japan

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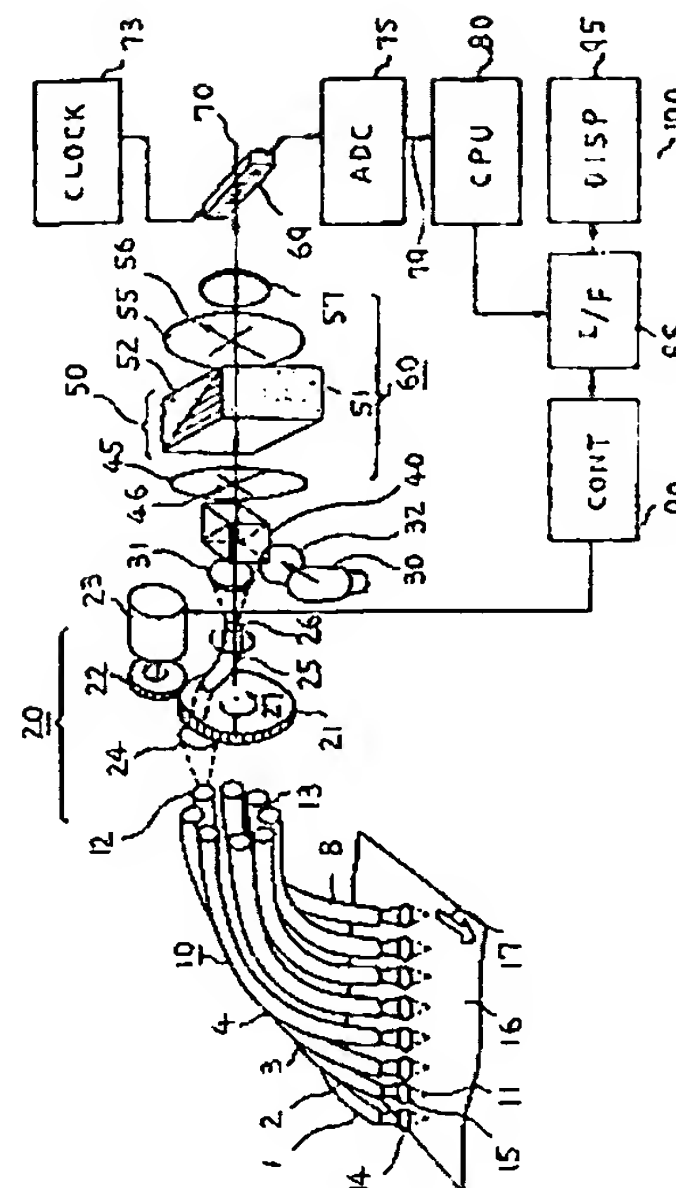
APPLICATION DATE : 15-03-89  
APPLICATION NUMBER : 01060996

APPLICANT : HITACHI LTD;

INVENTOR : SASADA KATSUHIRO;

INT.CL. : G01B 11/06 G01B 11/30

TITLE : MULTI-POINT FILM THICKNESS  
MEASURING APPARATUS



ABSTRACT : PURPOSE: To enable use in a wide production line by arranging other ends of a plurality of optical fibers facing points to be measured on a circumference to pick up a luminous flux from an optional optical fiber through an optical fiber selected rotating facing the ends.

CONSTITUTION: A plurality of optical fibers 1-8 are arranged at one end thereof to be movable in position facing points to be measured at a position predetermined while the other ends 12 thereof are arranged on a circumference. One selected optical fiber 25 is turned on the circumference to allow the picking up of luminous fluxes from optional optical fibers 1-8. This allows reflected light to be selected from a number of measuring points 11 sequentially and incident on an image interferometer 60 for forming an interference fringe in a space and thus, one interference fringe can be detected by a one-dimensional diode array or the like to measure a film thickness at a point involved by a calculation processing.

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